TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# T C 7 M H 3 7 4 F K

#### Octal D-Type Flip-Flop with 3-State Output

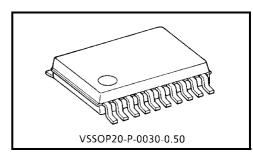
The TC7MH374FK is an advanced high speed CMOS octal flip-flop with 3-state output fabricated with silicon gate  $\rm C^2MOS$  technology.

It achieves the high speed operation similar to equivalent bipolar schottky TTL while maintaining the CMOS low power dissipation.

This 8-bit D-type flip-flop is controlled by a clock input (CK) and an output enable input ( $\overline{OE}$ ).

When the  $\overline{OE}$  input is high, the eight outputs are in a high impedance state.

An input protection circuit ensures that 0 to 7 V can be applied



Weight: 0.03 g (typ.)

to the input pins without regard to the supply voltage. This device can be used to interface 5~V to 3~V systems and two supply systems such as battery back up. This circuit prevents device destruction due to mismatched supply and input voltages.

#### **Features**

- High speed:  $f_{max} = 185 \text{ MHz}$  (typ.) (VCC = 5 V)
- Low power dissipation:  $ICC = 4 \mu A \text{ (max) (Ta} = 25 \text{°C)}$
- High noise immunity: V<sub>NIH</sub> = V<sub>NIL</sub> = 28% V<sub>CC</sub> (min)
- Power down protection is provided on all inputs.
- Balanced propagation delays:  $t_pLH \simeq t_pHL$
- Wide operating voltage range: VCC (opr) = 2~5.5 V
- Low noise: VOLP = 0.8 V (max)
- Pin and function compatible with 74ALS374

000630EBA1

In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc..

The products described in this document are subject to the foreign exchange and foreign trade laws

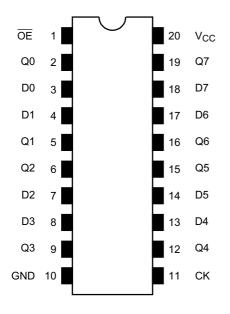
• The information contained herein is subject to change without notice.

TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general
can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the
buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and
to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or
damage to property.

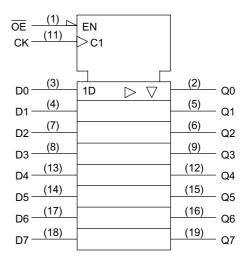
<sup>•</sup> The Toshiba products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.). These Toshiba products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of Toshiba products listed in this document shall be made at the customer's own risk.

The information contained herein is presented only as a guide for the applications of our products. No responsibility is assumed by TOSHIBA CORPORATION for any infringements of intellectual property or other rights of the third parties which may result from its use. No license is granted by implication or otherwise under any intellectual property or other rights of TOSHIBA CORPORATION or others

### Pin Assignment (top view)



### **IEC Logic Symbol**



#### **Truth Table**

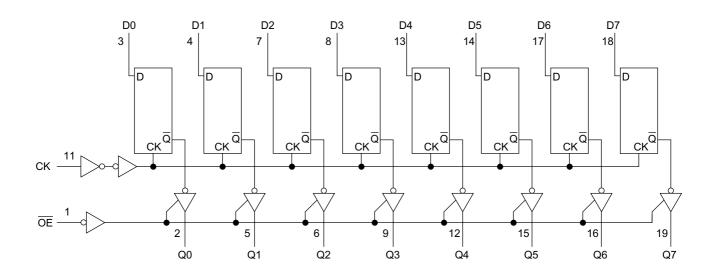
	Outputs		
ŌĒ	CK	D	Outputs
Н	Х	Х	Z
L	<b>—</b>	Х	Q <sub>n</sub>
L		L	L
L		Н	Н

X: Don't care

Z: High impedance

Q<sub>n</sub>: No change

### **System Diagram**





## **Maximum Ratings**

Characteristics	Symbol	Rating	Unit
Supply voltage range	V <sub>CC</sub>	-0.5~7.0	V
DC input voltage	V <sub>IN</sub>	-0.5~7.0	V
DC output voltage	V <sub>OUT</sub>	-0.5~V <sub>CC</sub> + 0.5	V
Input diode current	I <sub>IK</sub>	-20	mA
Output diode current	lok	±20	mA
DC output current	lout	±25	mA
DC V <sub>CC</sub> /ground current	I <sub>CC</sub>	±75	mA
Power dissipation	P <sub>D</sub>	180	mW
Storage temperature	T <sub>stg</sub>	-65~150	°C

## **Recommended Operating Conditions**

Characteristics	Symbol	Rating	Unit
Supply voltage	V <sub>CC</sub>	2.0~5.5	V
Input voltage	V <sub>IN</sub>	0~5.5	V
Output voltage	V <sub>OUT</sub>	0~V <sub>CC</sub>	V
Operating temperature	T <sub>opr</sub>	-40~85	°C
Input rise and fall time	dt/dv	$0\sim100 \ (V_{CC}=3.3\pm0.3 \ V)$	ns/V
input rise and rail time	αί/αν	$0\sim20 \ (V_{CC}=5\pm0.5 \ V)$	115/ V



### **Electrical Characteristics**

### **DC Characteristics**

Characteristics		Symbol Test Condition		Condition		Ta = 25°C			Ta = -40~85°C		Unit
Charac	Rensucs	Symbol			V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	Offic
					2.0	1.50	_	_	1.50	_	
Input voltage	High level	$V_{IH}$		_		V <sub>CC</sub> × 0.7	_	_	V <sub>CC</sub> × 0.7	_	V
input voitage					2.0	_	_	0.50	_	0.50	V
	Low level	$V_{IL}$		_	3.0~5.5	1	_	V <sub>CC</sub> × 0.3	_	V <sub>CC</sub> ×0.3	
					2.0	1.9	2.0		1.9		
		V <sub>ОН</sub>		$I_{OH} = -50 \mu A$	3.0	2.9	3.0		2.9	_	
	High level		V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>		4.5	4.4	4.5	_	4.4	_	
Output				$I_{OH} = -4 \text{ mA}$	3.0	2.58	_	_	2.48		V
				$I_{OH} = -8 \text{ mA}$	4.5	3.94	_	_	3.80	_	
voltage					2.0	_	0	0.1	_	0.1	V
			., .,	$I_{OL} = 50 \mu A$	3.0	_	0	0.1	_	0.1	
	Low level	$V_{OL}$	$V_{IN} = V_{IH}$ or $V_{IL}$		4.5	_	0	0.1	_	0.1	
				$I_{OL} = 4 \text{ mA}$	3.0	_	_	0.36	_	0.44	
	Ic		$I_{OL} = 8 \text{ mA}$	4.5	_	_	0.36	_	0.44		
3-state output	off-state current	I <sub>OZ</sub>	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = V_{CC} \text{ or GND}$		5.5	_	_	±0.25	_	±2.50	μА
Input leakage	current	I <sub>IN</sub>	V <sub>IN</sub> = 5.5 V or GND		0~5.5			±0.1	_	±1.0	μΑ
Quiescent sup	ply current	Icc	$V_{IN} = V_{CC}$	V <sub>IN</sub> = V <sub>CC</sub> or GND		_	_	4.0	_	40.0	μΑ



## Timing Requirements (Input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics	Symbol	Test Condition		Ta = 25°C		Ta = -40~85°C	Unit	
	Symbol	rest Condition	V <sub>CC</sub> (V)	Тур.	Limit	Limit	Offic	
Minimum pulse width	t <sub>w (H)</sub>		$3.3 \pm 0.3$	_	5.0	5.5	ne	
(CK)	t <sub>w (L)</sub>	_	$5.0 \pm 0.5$		5.0	5.0	ns	
Minimum set-up time	t <sub>s</sub>	_	$3.3\pm0.3$	_	4.5	4.5	ns	
			$5.0\pm0.5$		3.0	3.0	110	
Minimum hold time	t <sub>h</sub>		$3.3\pm0.3$	_	2.0	2.0	ns	
		_	$5.0\pm0.5$	_	2.0	2.0	115	

#### AC Characteristics (Input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics	Symbol Test Condition				Ta = 25°C			Ta = -40~85°C		Unit
Characteristics	Symbol	rest Condition	V <sub>CC</sub> (V)	C <sub>L</sub> (pF)	Min	Тур.	Max	Min	Max	Offic
			$3.3 \pm 0.3$	15	_	8.1	12.7	1.0	15.0	
Propagation delay time	t <sub>pLH</sub>		3.3 ± 0.3	50	_	10.6	16.2	1.0	18.5	ns
(CK-Q)	t <sub>pHL</sub>	_	5.0 ± 0.5	15	_	5.4	8.1	1.0	9.5	115
			3.0 ± 0.5	50	_	6.9	10.1	1.0	11.5	
			$3.3 \pm 0.3$	15	_	7.1	11.0	1.0	13.0	
3-state output enable time	t <sub>pZL</sub>	$R_L = 1 \text{ k}\Omega$	3.3 ± 0.3	50	_	9.6	14.5	1.0	16.5	ns
3-state output enable time	t <sub>pZH</sub>		5.0 ± 0.5	15	_	5.1	7.6	1.0	9.0	
			3.0 ± 0.5	50	_	6.6	9.6	1.0	11.0	
3-state output disable time	t <sub>pLZ</sub>	$R_L = 1 \text{ k}\Omega$	$3.3 \pm 0.3$	50	_	10.2	14.0	1.0	16.0	ns
3-state output disable time	t <sub>pHZ</sub>		$5.0 \pm 0.5$	50	_	6.1	8.8	1.0	10.0	
	f <sub>max</sub>	_	3.3 ± 0.3	15	80	130	_	70	_	- MHz
Maximum clock frequency				50	55	85	_	50	_	
Maximum clock frequency			5.0 ± 0.5	15	130	185	_	110	_	
				50	85	120	_	75	_	
Output to output skew	t <sub>osLH</sub>	(Note1)	$3.3 \pm 0.3$	50	_	_	1.5	_	1.5	no
Output to output skew	t <sub>osHL</sub>	(Note I)	$5.0 \pm 0.5$	50	_	_	1.0	_	1.0	ns
Input capacitance	C <sub>IN</sub>				_	4	10	_	10	pF
Output capacitance	C <sub>OUT</sub>	-	_		_	6	_	_	_	pF
Power dissipation capacitance	C <sub>PD</sub>			(Note2)	_	32	_	_	_	pF

Note1: This parameter is guaranteed by design.

 $t_{OSLH} = |t_{DLHm} - t_{DLHn}|, t_{OSHL} = |t_{DHLm} - t_{DHLn}|$ 

Note2: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/8 (per F/F)$ 

And the total C<sub>PD</sub> when n pcs of latch operate can be gained by the following equation:

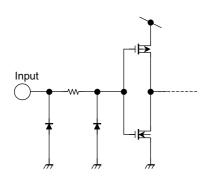
 $C_{PD}$  (total) = 20 + 12• n



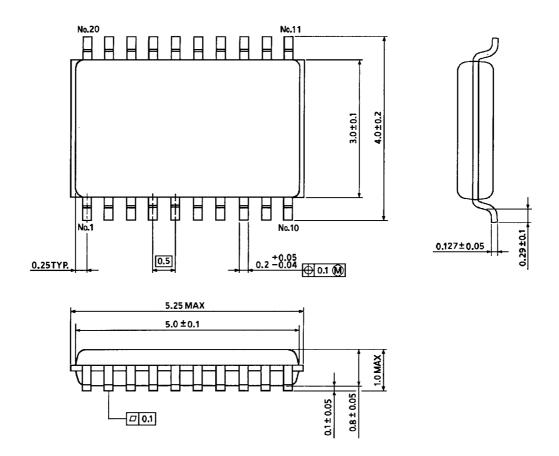
## Noise Characteristics (Input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics	Symbol	Test Condition		Ta = 25°C		Unit
Gilalacteristics	Syllibol	rest Condition	V <sub>CC</sub> (V)	Тур.	Limit	Offic
Quiet output maximum dynamic V <sub>OL</sub>	V <sub>OLP</sub>	C <sub>L</sub> = 50 pF	5.0	0.5	8.0	V
Quiet output minimum dynamic V <sub>OL</sub>	V <sub>OLV</sub>	C <sub>L</sub> = 50 pF	5.0	-0.5	-0.8	V
Minimum high level dynamic input voltage $V_{\text{IH}}$	V <sub>IHD</sub>	C <sub>L</sub> = 50 pF	5.0	_	3.5	V
Maximum low level dynamic input voltage $V_{\text{IL}}$	V <sub>ILD</sub>	C <sub>L</sub> = 50 pF	5.0	_	1.5	V

## **Input Equivalent Circuit**



## **Package Dimensions**



Weight: 0.03 g (typ.)